

Search Notes

Application/Control No.

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Examiner

Christopher H. Yaen

Applicant(s)/Patent under
Reexamination

LIOUBIN ET AL.

Art Unit

1642

SEARCHED

Class	Subclass	Date	Examiner
Updated		3/10/2005	CHY

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
435	7.1	3/15/2005	CHY
stic seq search SEQ ID No: 2		3/15/2005	CHY

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Updated searches	3/10/2005	CHY
STIC seq search SEQ ID No: 2	3/10/2005	CHY